

<b>Notice of References Cited</b>	Application/Control No. 10/534,069		Applicant(s)/Patent Under Reexamination IIMORI, YASUO	
	Examiner Russell Frejd		Art Unit 2128	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,439,059	08-2002	Inoue et al.	73/812
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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	X	CHIANG, Y.J. Characterizing simple-stranded wire cables under axial loading, Finite Elements in Analysis and Design, Vol. 24, December 1996, pp. 49-66.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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